



INFORMATION SUBMITTED BY APPLICANT(S) THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicant: T.-Y. Chang et al. Attorney Docket No. SIPT121256
Application No.: 10/601,709 Group Art Unit: ---
Filed: June 19, 2003 Examiner: ---
Title: INTEGRATED CIRCUIT DEVICE WITH A BUILT-IN DETECTING CIRCUIT FOR DETECTING MAXIMUM MEMORY ACCESS TIME OF AN EMBEDDED MEMORY

U.S. PATENT DOCUMENTS

*Examiner Cite Initials	Cite No.	Kind Document No.	Date (mm/dd/yyyy)	Name
CA	U1	6,424,583 ✓	07/23/2002	Sung et al.

FOREIGN PATENT DOCUMENTS

*Examiner Cite Initial	Cite No.	Kind Document No.	Publication Date (mm/dd/yyyy)	Country	English Abstract Provided	Translation Provided
None.						

OTHER INFORMATION
(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Cite Initial	Cite No.	Author, Title, Date, Pertinent Pages, Etc.
CA	O1	Sung and Wu, <i>A Method of Embedded Memory Access Time Measurement</i> , IEEE, 462-465 (2001)
CA	O2	Lee, Hsiao and Chang, <i>An Access Timing Measurement Unit of Embedded Memory</i> , IEEE, 104-109 (2002)

Examiner Date Considered
SON DINH 5/15/04

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
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